10/618,850

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Ref #	Hits	Search Query	DBs	Default Default	Plurals	Time Stamp
L3	1028	438/30	USPAT	OR	ON	2005/07/06 16:37
L4	227	438/45	USPAT	OR	ON	2005/07/06 16:37
L5	926	438/46	USPAT	OR	ON	2005/07/06 16:37
L6	59	438/77	USPAT	OR	ON	2005/07/06 16:37
L7	548	438/154	USPAT	OR	ON	2005/07/06 16:38
L8	421	438/157	USPAT	OR	· ON	2005/07/06 16:38
L9	242	438/159	USPAT	OR	ON	2005/07/06 16:38
L10	570	438/163	USPAT	OR	ON	2005/07/06 16:38
L11	638	438/164	USPAT	OR	ON	2005/07/06 16:38
L12	49	438/191	USPAT	OR	ON	2005/07/06 16:38
L13	1734	438/197	USPAT	OR	ON	2005/07/06 16:38
L14	95	438/181	USPAT	OR	ON	2005/07/06 16:38
L15	161	438/194	USPAT	OR	ON	2005/07/06 16:38
L16	153	438/174	USPAT	OR	ON	2005/07/06 16:38
L17	731	438/217	USPAT	OR	ON	2005/07/06 16:39
L18	1977	438/706	USPAT	OR	ON	2005/07/06 16:39
S16 4	1	10/295886	USPAT	OR	ON	2005/07/06 12:05
S16 5	2	09/438432	USPAT	OR	ON	2005/07/06 12:11
S16 6	1	("6635505").PN.	USPAT	OR	OFF	2005/07/06 14:01
S16 7	1	("6489952").PN.	USPAT	OR	OFF	2005/07/06 12:11
S16 8	199	(first adj impurity adj regions) and (second adj impurity adj regions) and (third adj impurity adj regions) and wirings	USPAT	OR	ON	2005/07/06 14:29
S16 9	7	(first adj impurity adj regions) and (second adj impurity adj regions) and (third adj impurity adj regions) and wirings and (active adj matrix adj type adj semiconductor)	USPAT	OR	ON	2005/07/06 14:05
S17 0	1	("4616243").PN.	USPAT	OR	OFF	2005/07/06 14:29

S17	1	S170 and (impurity or regions or first or second or third or fourth or	USPAT	OR	ON	2005/07/06 16:37
		insulating or gate or electrode or wiring or wirings or phosphorus or circuit or element or edge or boundary or aligned or region or				
		higher or semiconductor or portion)				